Search Notes

App	licat	ion/C	ontro	No.

Applicant(s)/Patent under Reexamination HECK ET AL.

10/611,334

Examiner

Art Unit 2823

Hsien-ming Lee

	SEARCHED				
Class	Subclass	Date	Examiner		
438	25,51	8/13/2007	LEE		
438	106-108	8/13/2007	LEE		
257	414,678	8/13/2007	LEE		
257	684,704	8/13/2007	LEE		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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